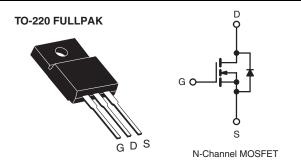


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	3.0		
Q _g (Max.) (nC)	78			
Q _{gs} (nC)	9.6			
Q _{gd} (nC)	45			
Configuration	Single			



FEATURES

- Isolated Package
- High Voltage Isolation = 2.5 kV_{RMS} (t = 60 s; f = 60 Hz)



- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. The isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION				
Package	TO-220 FULLPAK			
Lead (Pb)-free	IRFIBE30GPbF			
	SiHFIBE30G-E3			
SnPb	IRFIBE30G			
	SiHFIBE30G			

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	800	V	
Gate-Source Voltage			V_{GS}	± 20	1 '	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I-	2.1	А	
		T _C = 100 °C	I _D	1.4		
Pulsed Drain Current ^a			I _{DM}	8.4	1	
Linear Derating Factor				0.28	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	240	mJ	
Avalanche Current ^a			I _{AR}	2.1	Α	
Repetitive Avalanche Energy ^a			E _{AR}	3.5	mJ	
Maximum Power Dissipation	ower Dissipation $T_C = 25$ °C			35	W	
Peak Diode Recovery dV/dtc			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6 22 or l	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 of M3 Screw			1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 102 \, \text{mH}$, $R_G = 25 \, \Omega$, $I_{AS} = 2.1 \, \text{A}$ (see fig. 12).
- c. $I_{SD} \le 4.1$ A, $dI/dt \le 100$ A/ μ s, $V_{DD} \le 600$ V, $T_{J} \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFIBE30G, SiHFIBE30G

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.6	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	800	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zara Cata Valtaga Drain Current	V _{DS} = 800 V, V _{GS} = 0 V		-	-	100		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V	V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C		-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 1.3 A^b$	-	-	3.0	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 50 V, I _D = 1.3 A ^b	1.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}		-	1300	-	- pF	
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	310		-
Reverse Transfer Capacitance	C _{rss}			-	190		-
Drain to Sink Capacitance	С		f = 1.0 MHz		12		-
Total Gate Charge	Qg		I _D = 4.1 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	78	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	9.6	
Gate-Drain Charge	Q _{gd}	7		-	-	45	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, I_{D} = 4.1 \text{ A},$ $R_{G} = 12 \Omega, R_{D} = 95 \Omega,$ see fig. 10^{b}		-	12	-	- ns
Rise Time	t _r			-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						•
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2.1	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	8.4	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 2.1 A, V _{GS} = 0 V ^b		-	-	1.8	٧
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 4.1 \text{ A, dl/dt} = 100 \text{ A/}\mu\text{s}^b$		-	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	on is don	is dominated by L _S and L _D)			

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

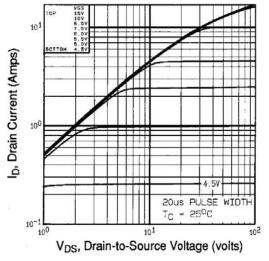


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

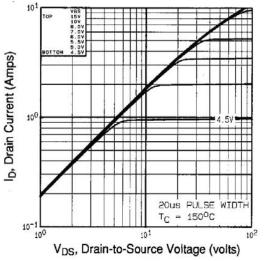


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

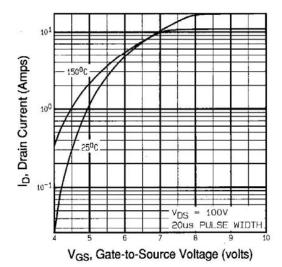


Fig. 3 - Typical Transfer Characteristics

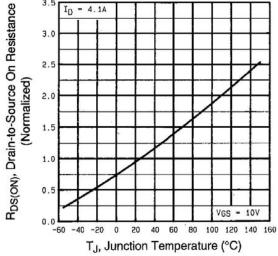


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFIBE30G, SiHFIBE30G

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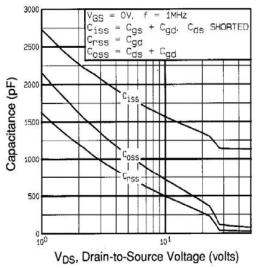
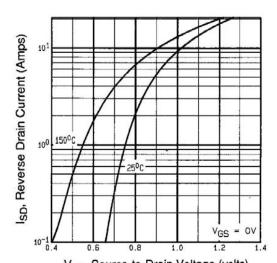


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



V_{SD}, Source-to-Drain Voltage (volts)
Fig. 7 - Typical Source-Drain Diode Forward Voltage

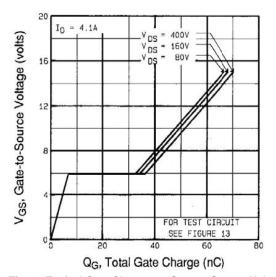


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

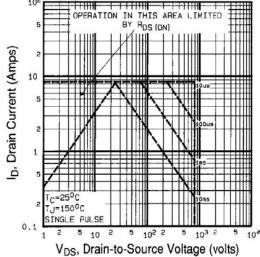


Fig. 8 - Maximum Safe Operating Area





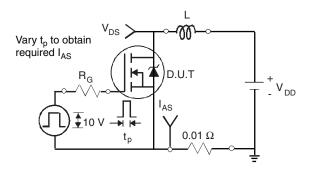


Fig. 9a - Unclamped Inductive Test Circuit

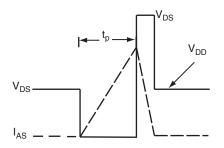


Fig. 9b - Unclamped Inductive Waveforms

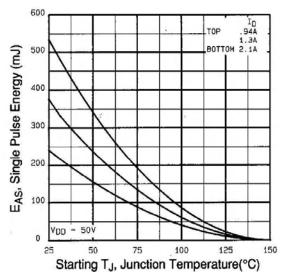


Fig. 9c - Maximum Avalanche Energy vs. Drain Current

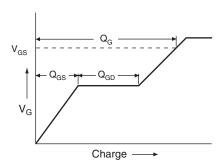


Fig. 10a - Basic Gate Charge Waveform

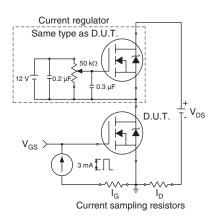
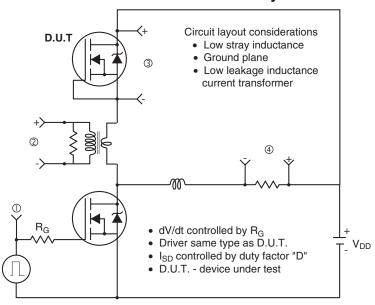


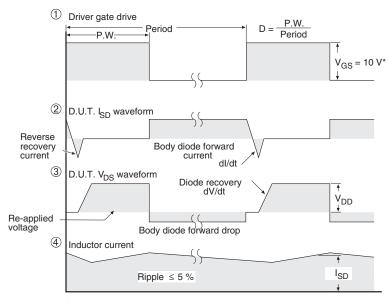
Fig. 10b - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 11 - For N-Channel

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